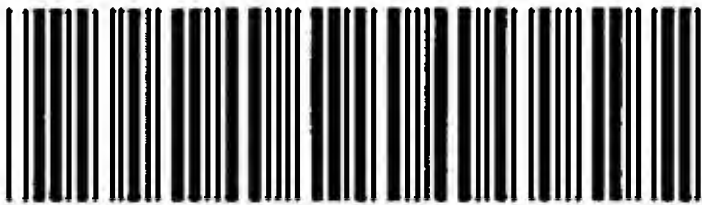


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/605,680	CHEN, CHIH-YUAN	
	<b>Examiner</b>	<b>Art Unit</b>	
	Christopher R. Lamb	2627	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted SPE Wayne Young regarding field of search	7/6/2006	CRL
EAST Search	7/6/2006	CRL